

JSM-IT300

Nova generacija vrstičnih elektronskih mikroskopov JEOL

- **Povečana zmogljivost nizkega vakuuma**
(650 Pa) (serijsko)
- **Nov način skeniranja – charge-free**
- **Nov, hitrejši in tišji oder za vzorce z veliko zmogljivostjo obremenitve**
(2 kg pri nagibu 90°)
- **Še več načinov detekcije**
(EDS / WDS / EBSD delovna razdalja 10 mm)
- **Visoko resolucijski okvir zajema slike (5120 x 3920 pik) serijsko**
- **Visoka zanesljivost**

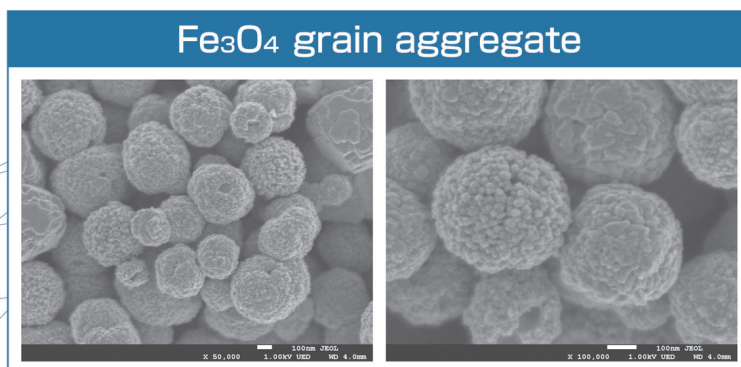
SCAN, d.o.o.

www.scan.si

Breg ob Kokri 7, SI-4205 Preddvor
tel: +386 (0)4 27 50 200
fax: +386 (0)4 27 50 240
e-mail: info@scan.si

Ultimate Analysis Tool Applicable for Wide Research Field

Thermal Field Emission Scanning Electron Microscope JSM-7800F



Photograph : Courtesy of WPPI-AIMR
Dr. Takanari Togashi
WPPI-AIMR = Tohoku University

Our super hybrid objective lens enables researchers to approach to the Nano World further. This objective lens can provide high resolution at a very low electron energy which is inevitable for nano structure observation of specimen surface. Our super hybrid objective lens enables high magnification observation and analysis even for magnetic material.

Ultimate Resolution

Our super hybrid objective lens provides high resolution of 0.8nm (15kV), 1.2nm(1kV). High performance electron optical system with built-in Gentle Beam displays fine structure of specimen surface. The distribution of composition can be observed at a low voltage of 0.5kV.

High Speed and High Accuracy Analysis

Our Aperture Angle Optimization Lens enables small electron probe diameter even if electric current is increased. By using large electric current, short time analysis is possible without degrading the quality of analysis accuracy or elemental map. Use of various analytical instruments such as EDS, WDS, and EBSD is possible. As the EBSD pattern with little distortion is possible to obtain, highly accurate crystal orientation analysis is possible.

Stable High Performance Data by Highly Stable Electron Probe

Thanks to in-lens thermal field emission electron source, electron probe which is stable for a long time can be obtained. High performance can be always possible. It is not necessary to wait until probe current becomes stable. Easy comparison of data obtained by several users, or data obtained on different day is possible.

High Performance for Any Kind of Specimen

Our super hybrid objective lens does not cause magnetic field at the analysis position. This can provide observation and analysis of magnetic materials at high magnification. Observation of non-conductive specimen can be easily done.